

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10813212	QUMEI, IYAD
	Examiner	Art Unit
	Chen, Shin-Hon	2131

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	6/13/07	S.C.

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
713	191, 193	4/15/11	S.C.
380	281,282,283, 285	4/15/11	S.C.
455	418,419	4/15/11	S.C.

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